

Notice of References Cited	Application/Control No. 10/711,271		Applicant(s)/Patent Under Reexamination EBEL ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,887,206 A	12-1989	Natarajan, Bharath	705/29
*	B	US-4,887,207 A	12-1989	Natarajan, Bharath	705/10
*	C	US-5,155,679 A	10-1992	Jain et al.	700/106
*	D	US-5,268,838 A	12-1993	Ito, Joji	700/99
*	E	US-5,287,267 A	02-1994	Jayaraman et al.	705/10
*	F	US-5,404,291 A	04-1995	Kerr et al.	705/5
*	G	US-5,630,070 A	05-1997	Dietrich et al.	705/8
*	H	US-5,841,659 A	11-1998	Tanaka et al.	700/121
*	I	US-5,884,276 A	03-1999	Zhu et al.	705/8
*	J	US-5,995,945 A	11-1999	Notani et al.	705/28
*	K	US-6,006,196 A	12-1999	Feigin et al.	705/10
*	L	US-6,021,396 A	02-2000	Ramaswamy et al.	705/28
*	M	US-6,044,356 A	03-2000	Murthy et al.	705/8

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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	U	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,041,267 A	03-2000	Dangat et al.	700/107
*	B	US-6,049,742 A	04-2000	Milne et al.	700/99
*	C	US-2001/0034673 A1	10-2001	Yang et al.	705/28
*	D	US-2002/0072956 A1	06-2002	Willems et al.	705/10
*	E	US-6,415,195 B1	07-2002	Gleditsch et al.	700/99
*	F	US-2002/0174000 A1	11-2002	Katz et al.	705/7
*	G	US-6,500,680 B1	12-2002	Tai et al.	438/6
*	H	US-2003/0033179 A1	02-2003	Katz et al.	705/7
*	I	US-2003/0050817 A1	03-2003	Cargille et al.	705/8
*	J	US-2003/0050870 A1	03-2003	Cargille et al.	705/28
*	K	US-2003/0101110 A1	05-2003	Chen et al.	705/29
*	L	US-6,615,092 B2	09-2003	Bickley et al.	700/99
*	M	US-2004/0024628 A1	02-2004	Eck et al.	705/8

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0034555 A1	02-2004	Dismukes et al.	705/7
*	B	US-2004/0148047 A1	07-2004	Dismukes et al.	700/100
*	C	US-2004/0225579 A1	11-2004	Peery et al.	705/028
*	D	US-2004/0260703 A1	12-2004	Elkins et al.	707/100
*	E	US-2006/0080294 A1	04-2006	Orumchian et al.	707/003
*	F	US-7,058,587 B1	06-2006	Horne, Martin	705/7
*	G	US-7,092,776 B2	08-2006	Torii et al.	700/99
*	H	US-7,181,501 B2	02-2007	Defosse, Erin M.	709/217
*	I	US-7,249,068 B1	07-2007	Kakouros et al.	705/28
*	J	US-7,546,225 B2	06-2009	Nguyen et al.	703/2
*	K	US-7,580,766 B1	08-2009	Sharma et al.	700/100
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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